Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/653,826	LAI ET AL.	
Examiner	Art Unit	
Tan V Mai	2103	

	SEARCHED				
Class	Subclass	Date	Examiner		
708	700, 708	9/20/2006	MAI		
					
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor(s) search Double Patent Check Data Bases Search (see search history printout)	9/20/2006	MAI		
Data Bases Search (see search history printout	9/22/2006	MAI		
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